

# An Overview of Relay Integrated Circuits and Technology

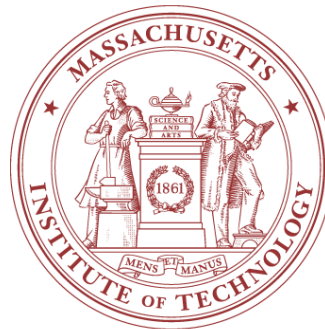
**Elad Alon (UC Berkeley)**

in collaboration with

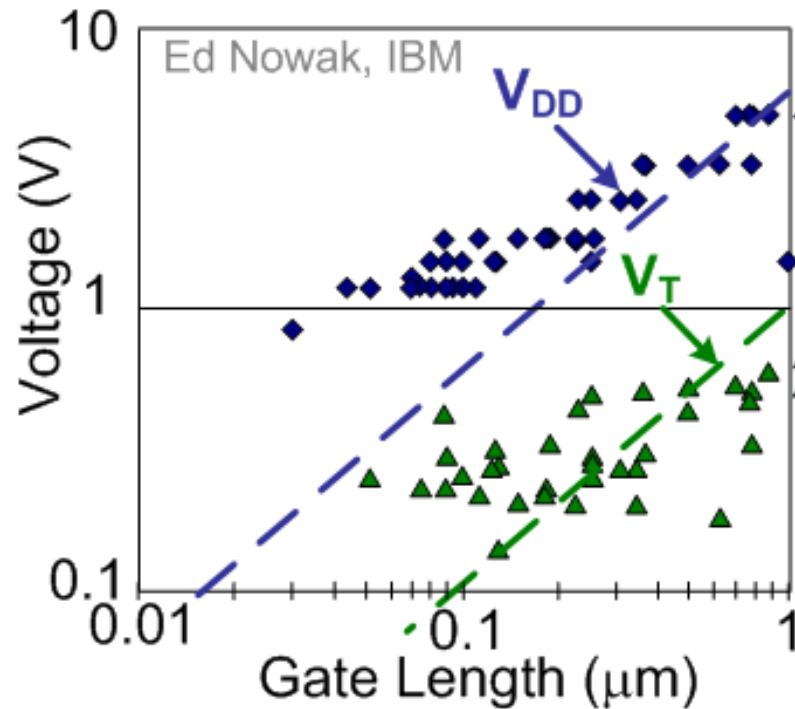
**Tsu-Jae King Liu (UC Berkeley),**

**Dejan Marković (UCLA),**

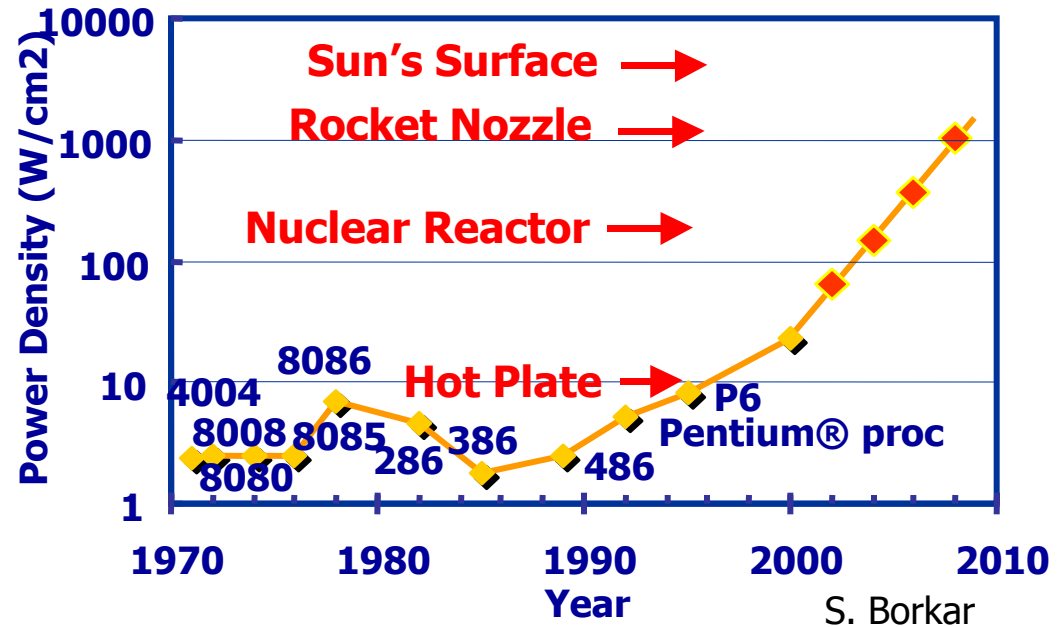
**Vladimir Stojanović (MIT)**



# Digital Computing Power Crisis

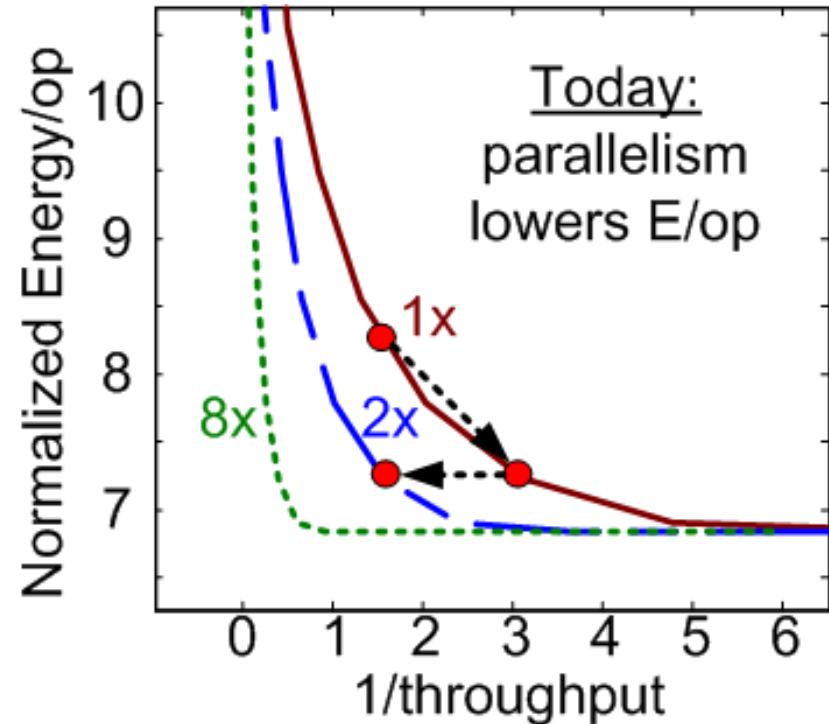
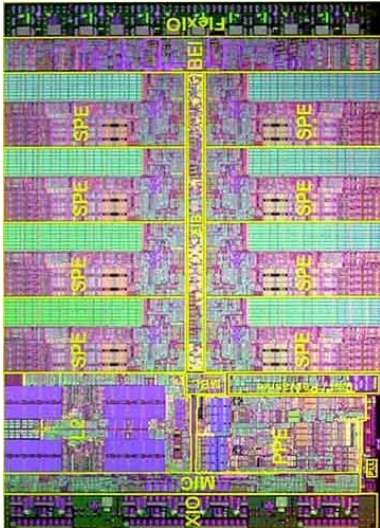


## Power Density Prediction circa 2000



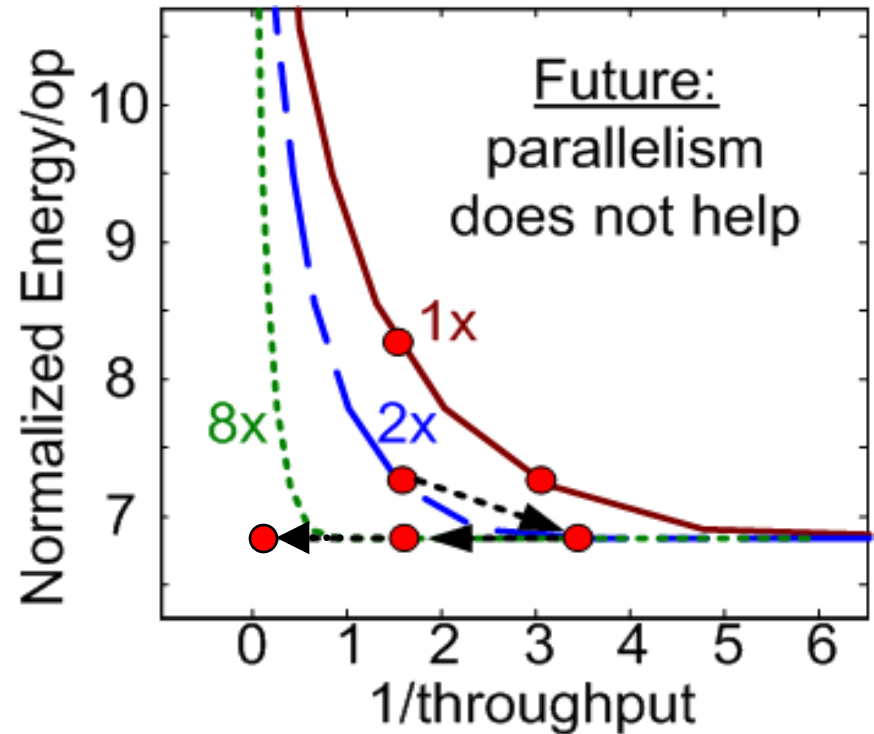
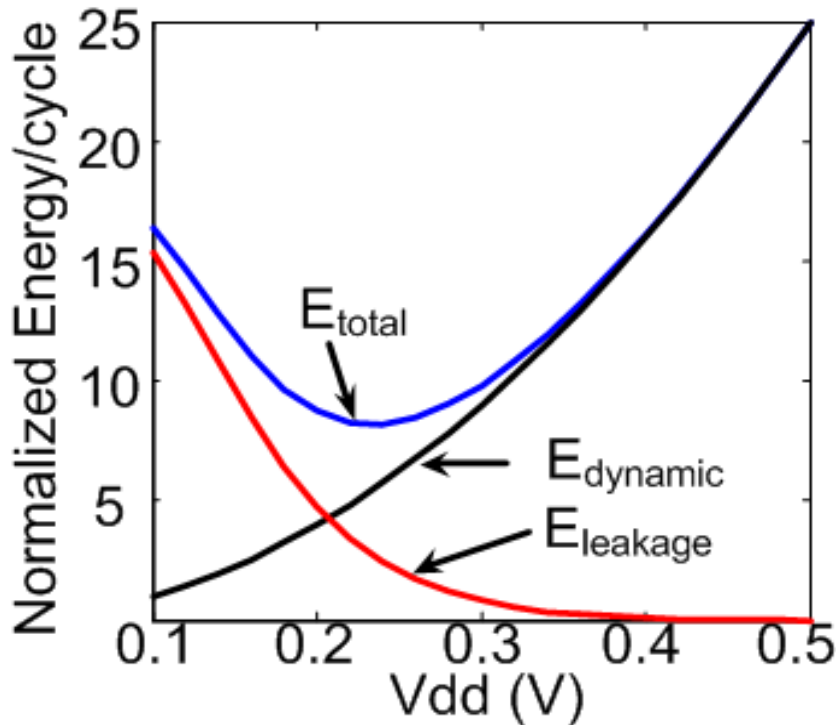
- Since ~2000 supply voltages ( $V_{DD}$ ) stuck at ~1V
  - Leakage stops you from lowering threshold ( $V_T$ )
- Leads to very poor power scaling... 1kW chips?

# Parallelism to the Rescue



- Parallelism allows slower, more efficient cores
  - While maintaining overall throughput
- Works well (if you can parallel program), but...

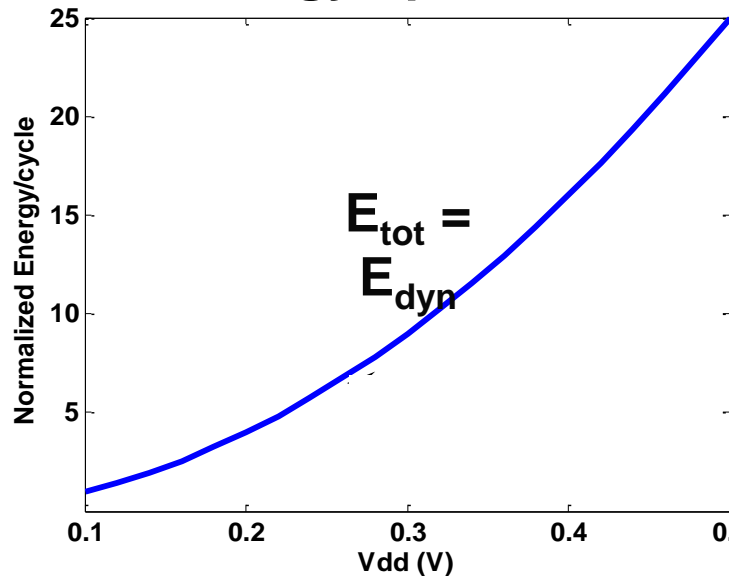
# Leakage: Game Over for CMOS



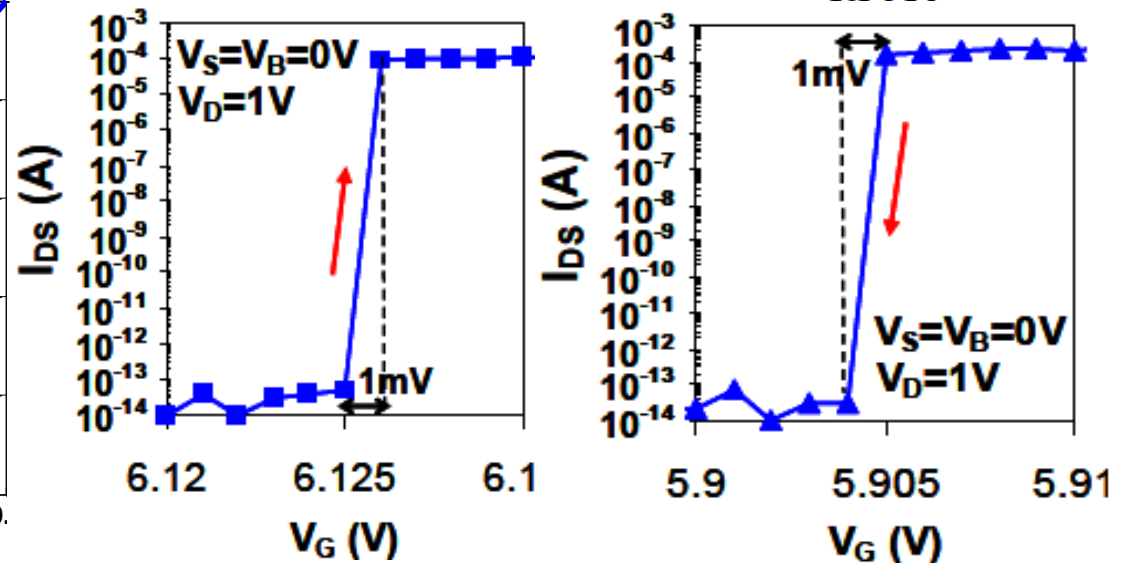
- ❑ **CMOS circuits have an absolute minimum energy**
  - ❑ Need to balance leakage and dynamic components
- ❑ **Parallelism doesn't help if already at  $E_{min}$ ...**

# Relays To The Rescue?

## Energy/op vs. Vdd



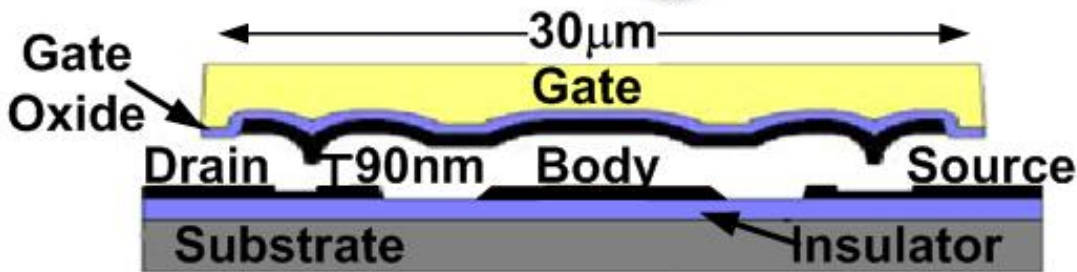
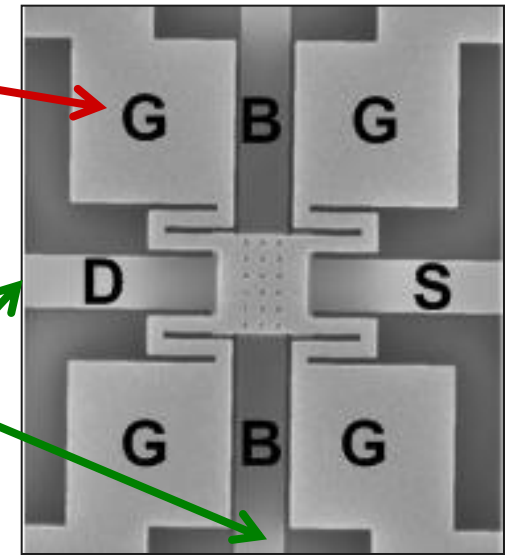
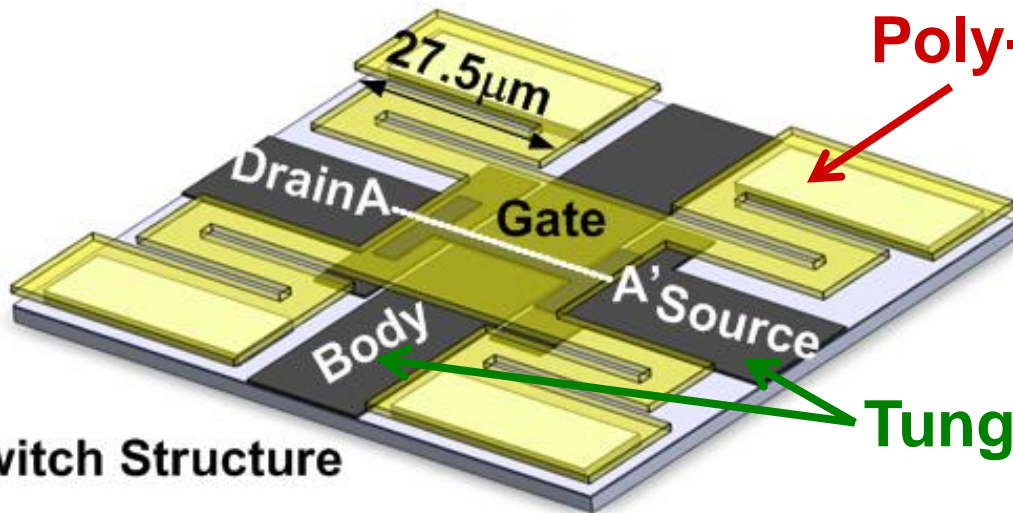
## Measured MEM Relay IV\*



- ❑ Mechanical relays don't leak, turn on abruptly
  - ❑ Potential pathway to continued energy scaling
- ❑ Device/circuit co-design critical

R. Nathanael *et al.*, "4-Terminal Relay Technology for Complementary Logic,"  
*IEDM 2009*

# Relay Structure and Operation



A-A' cross-section: *off-state*



A-A' cross-section: *on-state*

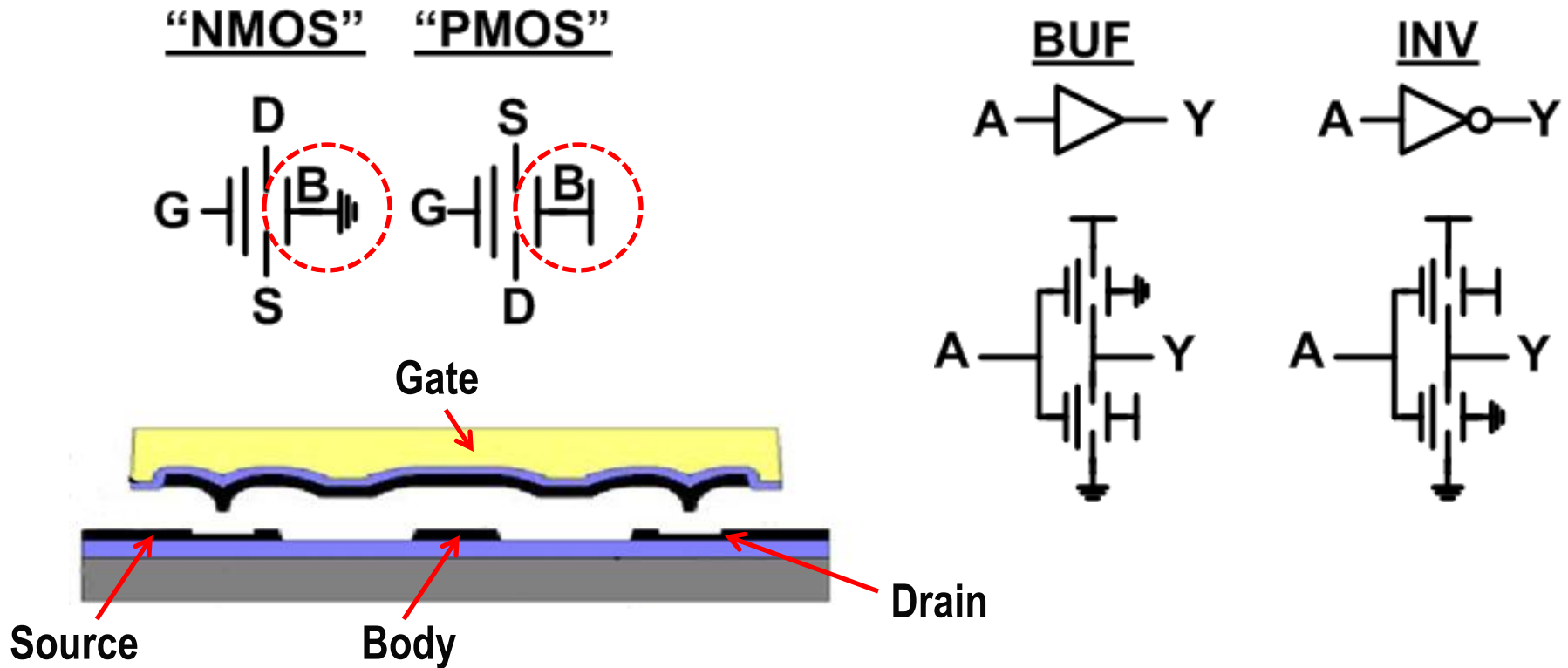
OFF:

$$|V_{gb}| < V_{po} \text{ (pull-out)}$$

ON:

$$|V_{gb}| > V_{pi} \text{ (pull-in)}$$

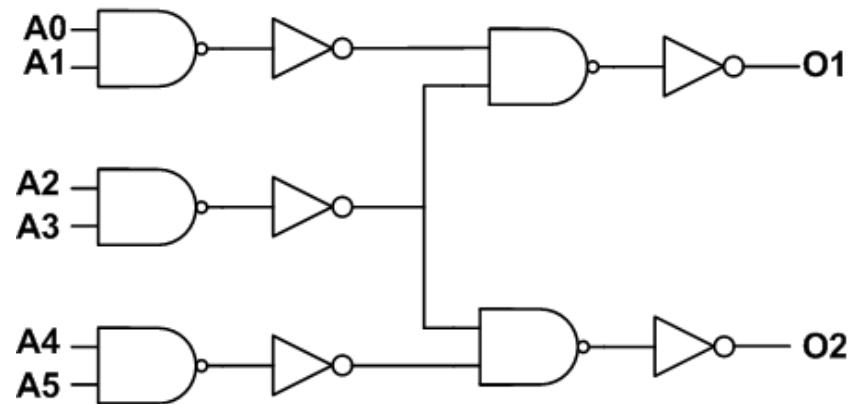
# NEM Relay as a Logic Element



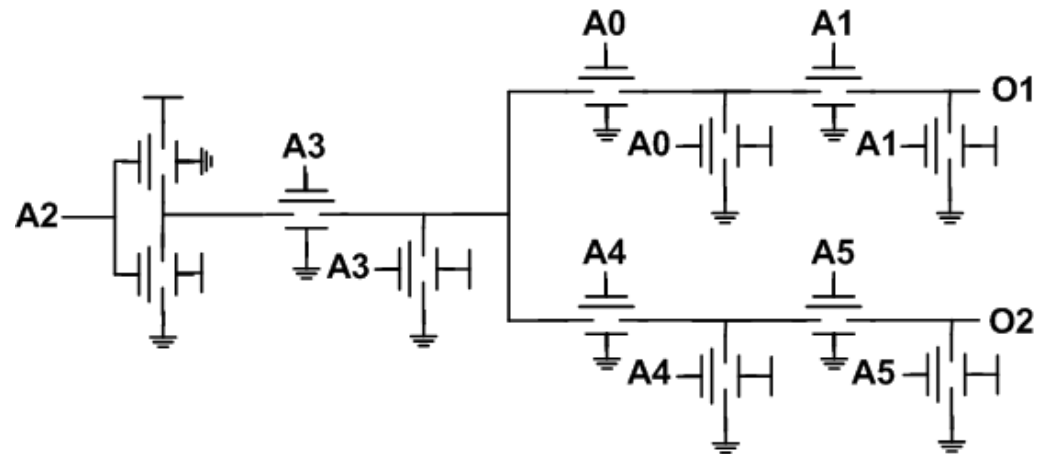
- ❑ **Mimics operation of CMOS transistors**
  - ❑ Electrostatic actuation is ambipolar
- ❑ **Unlike CMOS, non-inverting logic is possible**
  - ❑ Switch state set only by gate-to-body voltage

# Digital Circuit Design with NEM Relays

CMOS: 30 transistors



NEMS: 12 switches

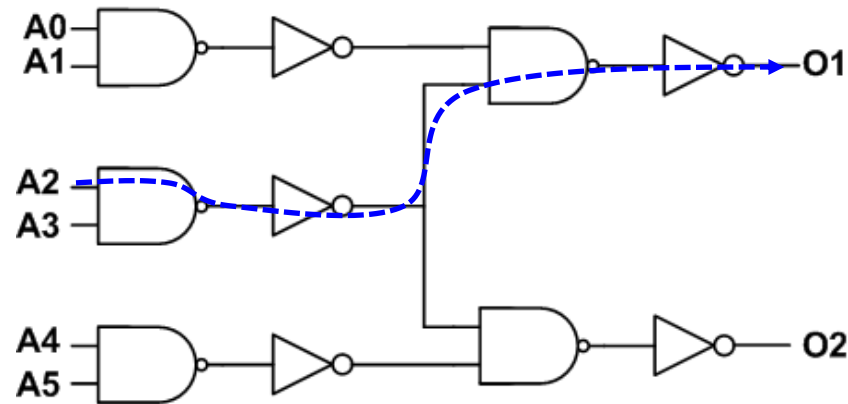


- ❑ **CMOS: delay set by electrical time constant**
  - ❑ Cascade simple gates to distribute fanout
- ❑ **Relays: delay dominated by mechanical movement**
  - ❑ So, want all to switch simultaneously
  - ➔ **Implement logic as a single complex gate (1930's)**



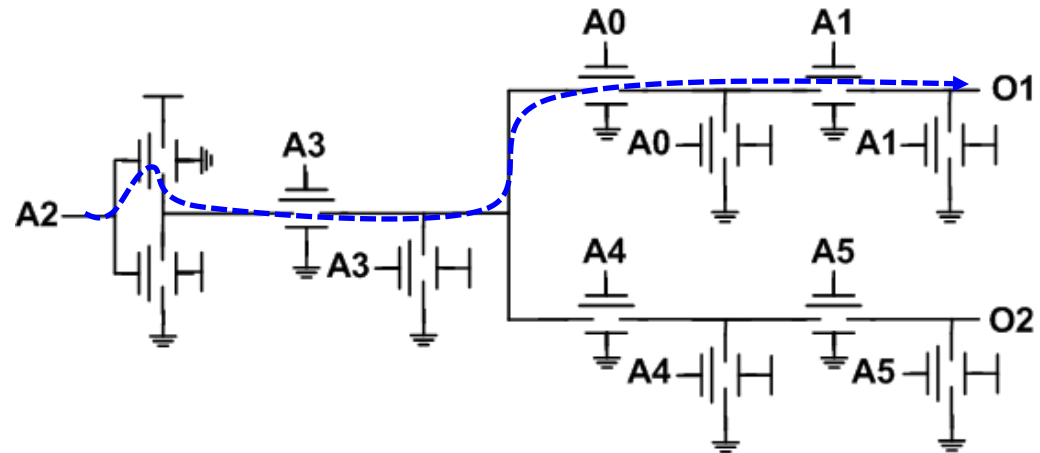
# Need to Compare at Block Level

CMOS: 30 transistors



4 gate delays →

NEMS: 12 relays

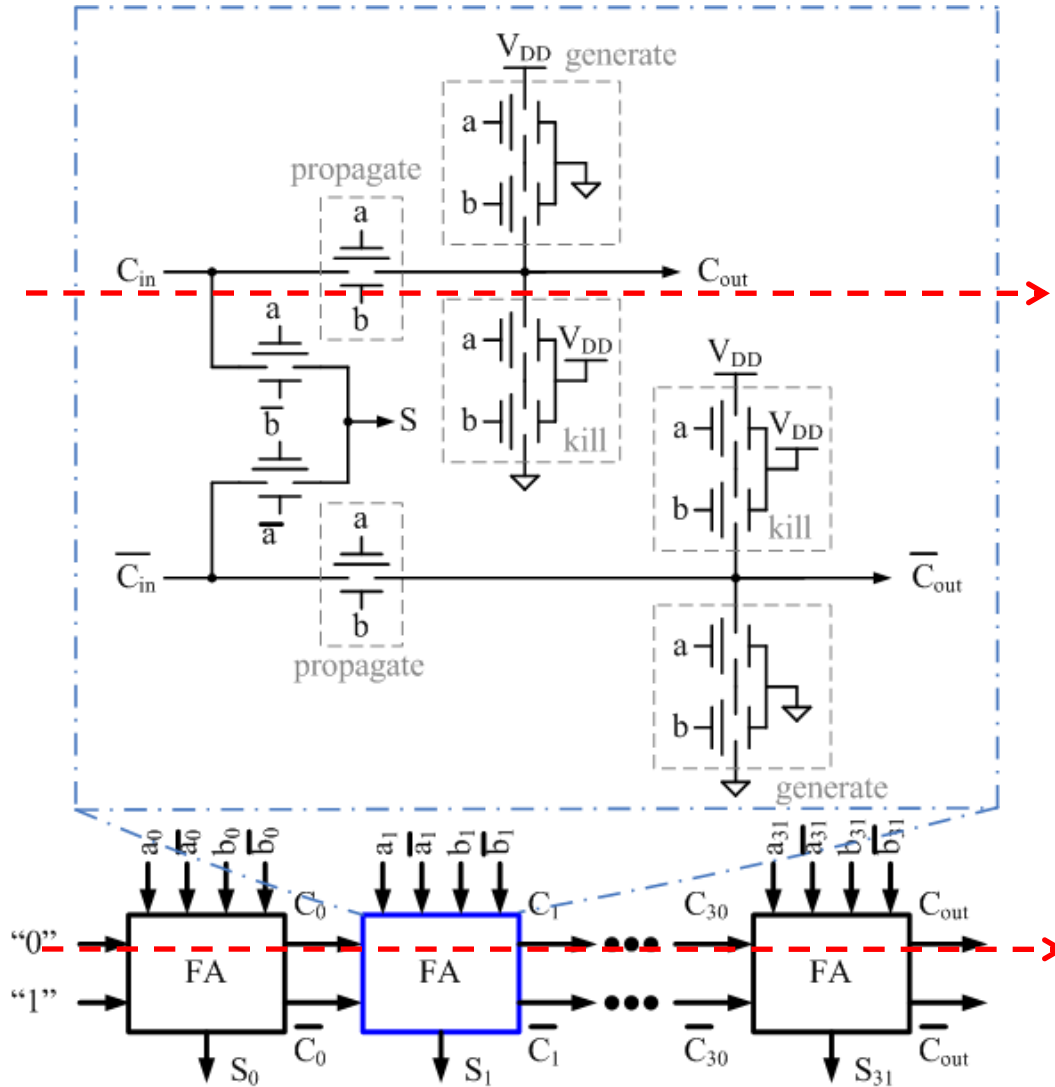


1 mechanical delay →

- ❑ **Single mechanical delay per block**
  - ❑ Substantially mitigates perceived delay disadvantage
- ❑ **Often fewer devices for same function**
  - ❑ Comparable area despite larger individual devices

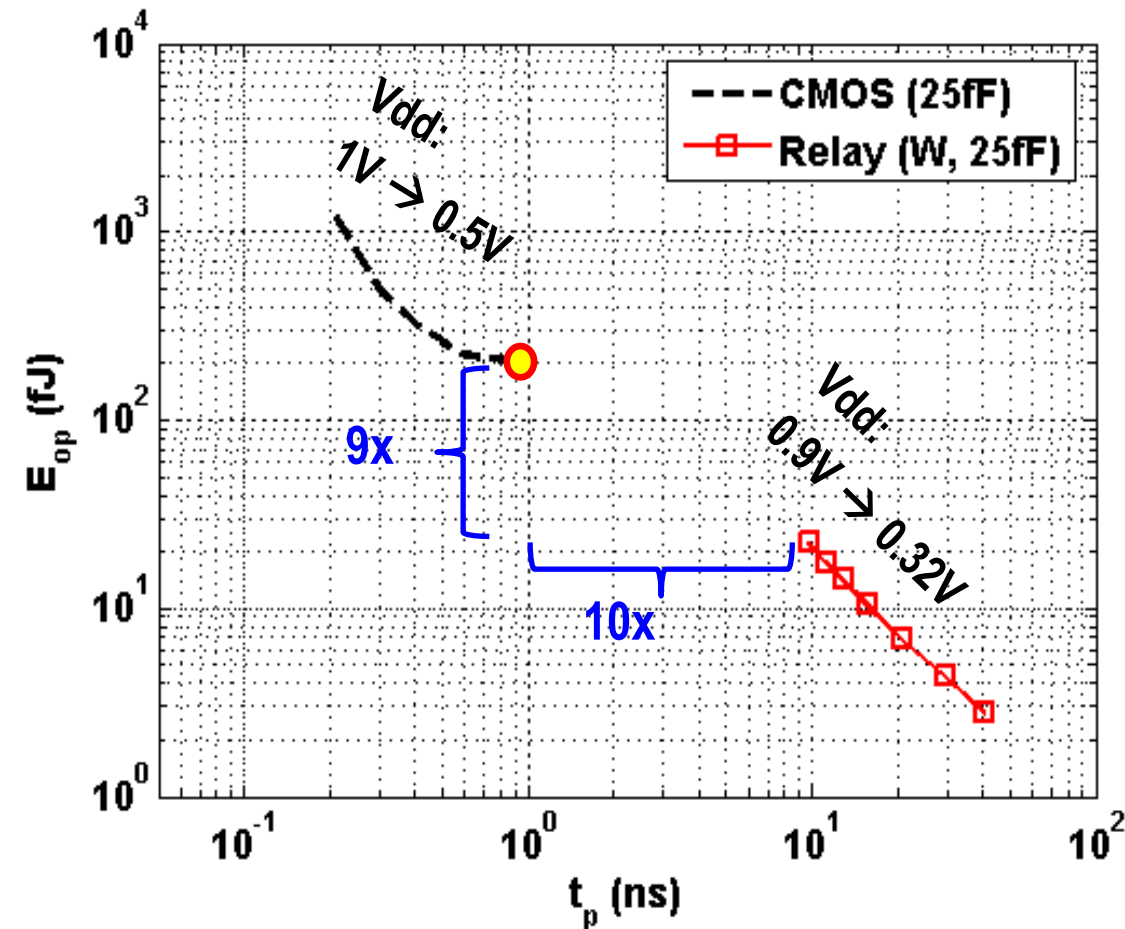
F. Chen *et al.*, "Integrated Circuit Design with NEM Relays," *ICCAD 2008*

# Example: 32-bit Relay Adder



- **Ripple carry configuration**
  - Cascade full adder cells to create larger complex gate
- **Stack of 32 relays, still a single mechanical delay**

# Scaled Relay vs. CMOS Adders

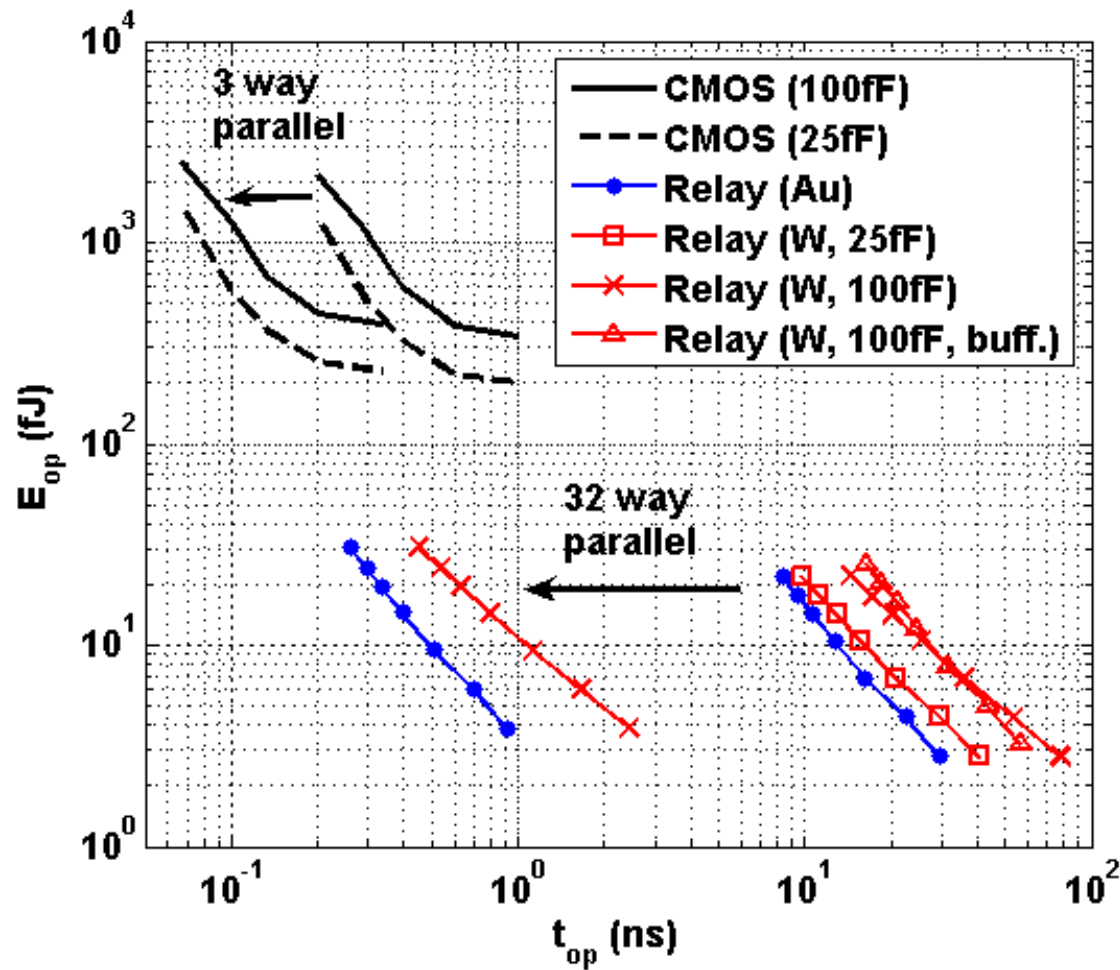


- Compare vs. CMOS adder\* in 90nm technology

- For similar area:
  - >9x lower E/op
  - >10x greater delay

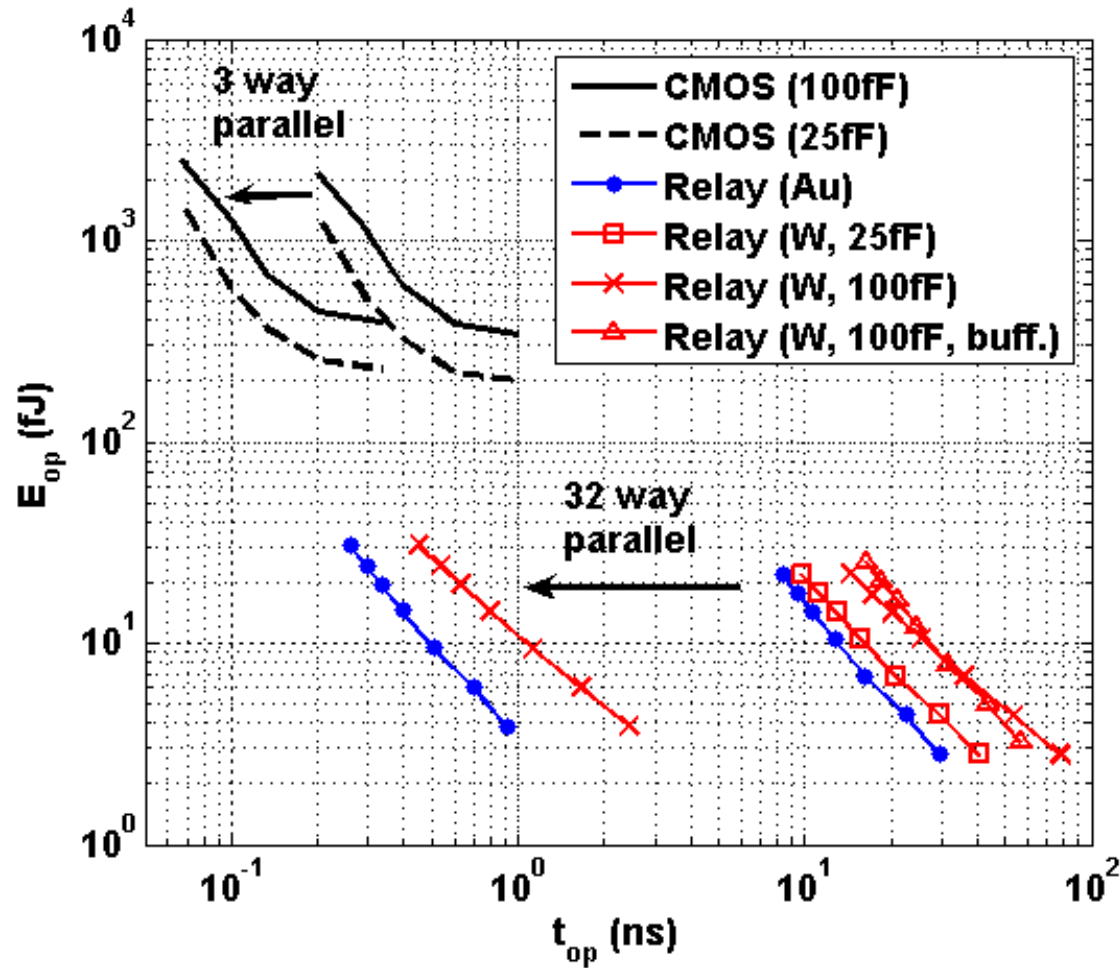
\* D. Patil *et al.*, "Robust Energy-Efficient Adder Topologies," *ARITH 2007*

# Parallelism



- Can extend energy benefit up to GOPS throughput
- As long as parallelism is available

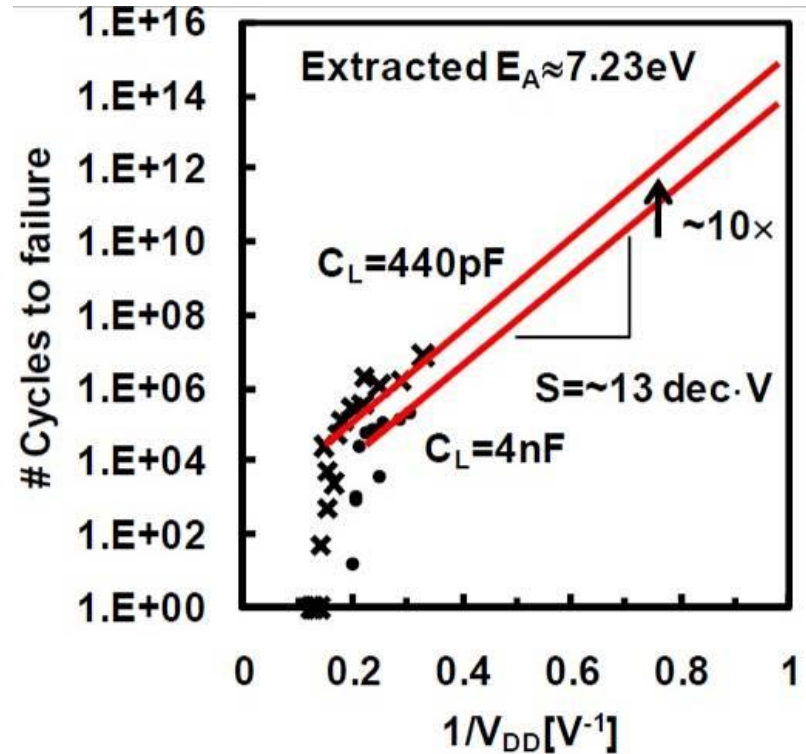
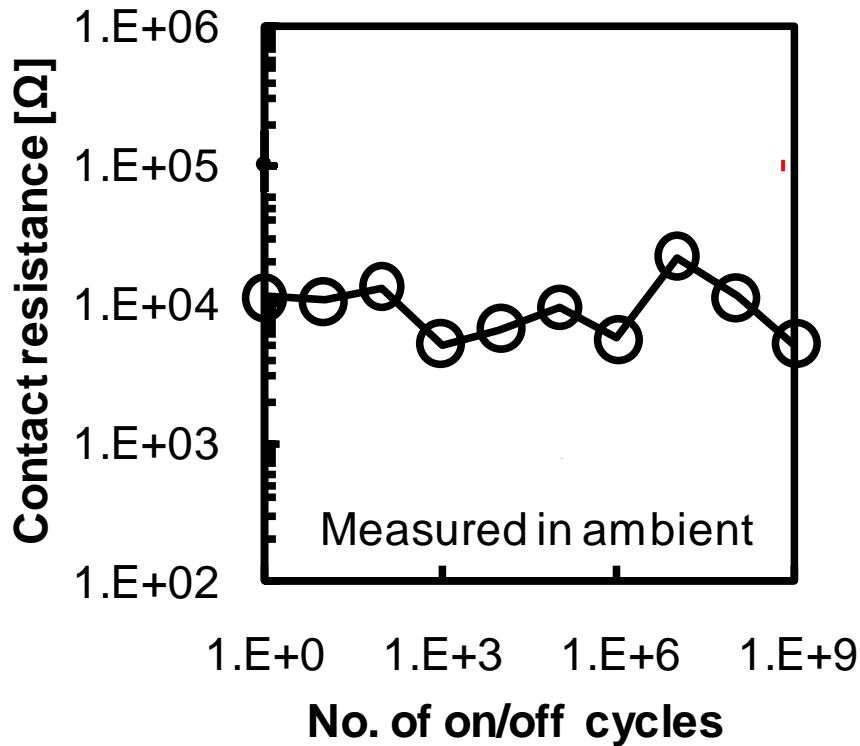
# Contact Resistance



□ Low contact R not critical

□ Good news for reliability...

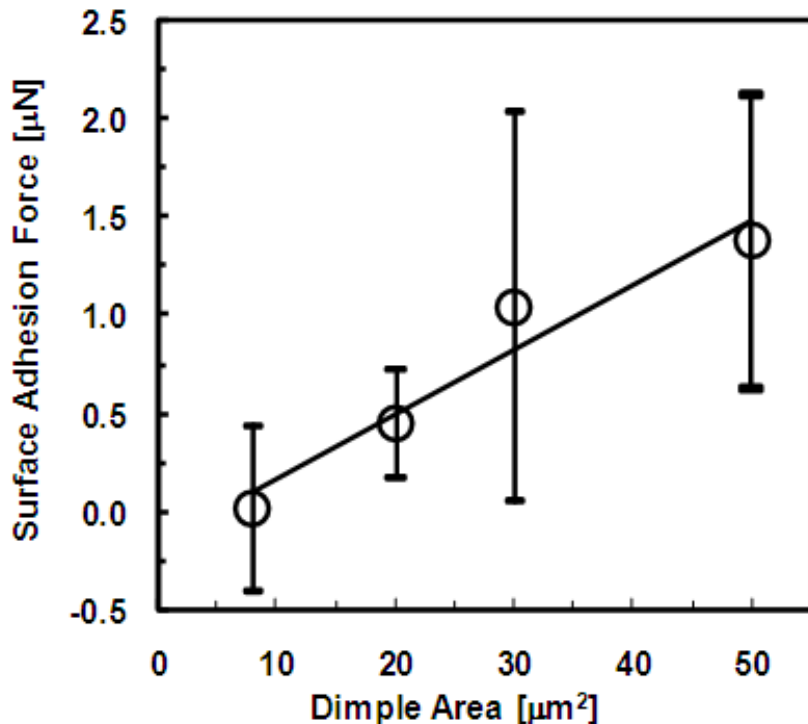
# Relay Contact Reliability



- Higher contact R, hard contact (W) improves reliability
  - Limits power dissipation, material flow
- Current endurance record: 65 billion cycles
  - Theory/experiments predict  $>10^{15}$  cycles @ 1V VDD

# Relay Energy Limit

- Spring force must be able to overcome surface adhesion force  $F_A$ :
  - $E_{\min} = 2F_A g_d \approx 2E_{\text{surf}}$
- For large contacts,  $F_A$  scales with area



- Extracted surface adhesion energy  $\sim 5\mu\text{J}/\text{m}^2$ 
  - 90nm x 90nm:  $E_{\text{surf}} = .04\text{aJ}$ !
- Ultimate energy limit set by # of contact bonds
  - $\sim 0.2\text{aJ}$  per bond

# Conclusions

- **Relay characteristics enable energy scaling beyond CMOS**
  - Nearly ideal  $I_{on}/I_{off}$
  - Need to adapt circuit design style
- **Reliability improving**
  - Circuit level insights critical (contact R)
- **Potential for 10X or more lower E/op than CMOS**
  - How to build complex relay-based systems?
  - Will this really work in practice?